

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1(currently amended). A probe comprising:

- (a) a substantially rigid support comprising a base and a planar circuit board having a resistor-capacitor network, said planar circuit board inclined with respect to said base; and
- (b) a plurality of contact fingers supported by and extending from said support, wherein said contact fingers are interconnected with said circuit board and are arranged as a unity assembly, wherein said plurality of contact fingers are maintained in a predetermined alignment when attached to said support by a tab proximate the ends of said plurality of contact fingers.

2(original). The probe of claim 1 wherein a plurality of said contact fingers extend in a radially outward direction from said support.

3(original). The probe of claim 2 wherein the arrangement of said contact fingers match the geometry of a contacting pads on a device under test.

4-5(canceled).

6(original). The probe of claim 1 wherein said unitary assembly includes a tab proximate the ends of said plurality of contact fingers that maintains said contact fingers in said predetermined alignment.

7(original). The probe of claim 6 wherein said tab is removed prior to probing with said contact fingers.

8(original). The probe of claim 1 wherein said rigid support includes a respective trace for each of said contact fingers.

9(original). The probe of claim 8 wherein said respective traces are electrically interconnected to a connector suitable to interconnect to test equipment.

10(original). The probe of claim 7 wherein said removal of said tab leaves the ends of each of said plurality of contact fingers in a predetermined position.

11(original). The probe of claim 1 wherein said plurality of contact fingers is greater than three.

12-22(canceled).

23(new). A probe comprising:

(a) a substantially rigid support comprising a planar circuit board having a resistor-capacitor network; and

(b) a plurality of contact fingers supported by and extending from said support, wherein said contact fingers are interconnected with said support by a soldered connection, wherein said plurality of contact fingers are maintained in a predetermined alignment when soldered to said support by a tab proximate the ends of said plurality of contact fingers.

24(new). The probe of claim 23 wherein a plurality of said contact fingers extend in a radially outward direction from said support.

25(new). The probe of claim 24 wherein the arrangement of said contact fingers match the geometry of a contacting pads on a device under test.

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26(new). The probe of claim 23 wherein said unitary assembly includes a tab proximate the ends of said plurality of contact fingers that maintains said contact fingers in said predetermined alignment.

27(new). The probe of claim 26 wherein said tab is removed prior to probing with said contact fingers.

28(new). The probe of claim 21 wherein said rigid support includes a respective trace for each of said contact fingers.

29(new). The probe of claim 28 wherein said respective traces are electrically interconnected to a connector suitable to interconnect to test equipment.

30(new). The probe of claim 27 wherein said removal of said tab leaves the ends of each of said plurality of contact fingers in a predetermined position.

31(new). The probe of claim 21 wherein said plurality of contact fingers is greater than three.